

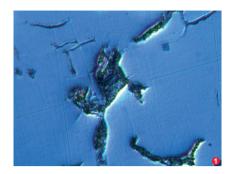
Leica DM1750 M

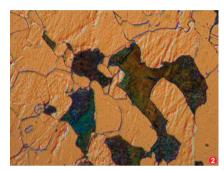
Cost effective solution for routine $\ensuremath{\text{QC}}$ in materials labs



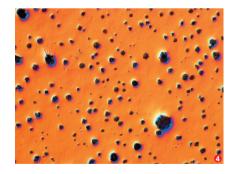
Living up to Life

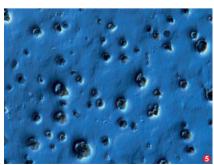
Research Quality at a Routine Price











With strong focus on the needs of routine tasks in the QC lab

The new Leica DM1750 M is a material microscope designed for rapid, accurate results even in rough industrial environments.

A high performance optical system is integrated within the robust design of the DM1750 M, which allows the inspection of various kinds of samples.

The reflected light illumination is based on Power-LEDs that provide highly intense, yet even illumination with natural colors for brilliant results. Additionally, the illumination axis is capable of changing illumination angles, to produce a relief (or a three dimensional impression), that is helpful to detect micro scratches or to gain relative height information.

Leica DM1750 M	
Stand	Robust material inspection microscope stand
Reflected light axis	LED 4 segment illumination for oblique investigations – LED-lifetime 20+ years – Contrasting modes: Brightfield, Differential Interference Contrast, Polarization – Built-in adjustable aperture diaphragm – POL observation using polarizer/analyzer
Focusing	 2-gear focusing (coarse/fine with 1 μm micrometer scale with top focus stop) or 3-gear focusing (coarse) (focus stop), (medium), fine with 1 and 4 μm micrometer scales, Torque adjustment, sample protection stop, height adjustable focus knobs
Tubes	 Binocular tube 30° or 45° w/wo integrated eyepieces Trinocular camera tube 30° or 45° w/wo integrated eyepieces Upright image binocular/trinocular tube 10x/20 FOV fixed eyepieces, 10x/20 FOV focusing eyepieces, 10x/22 FOV focusing eyepieces
Objective turret/objectives	6x BF M25 and 7x BF M25 objective turret HI PLAN EPI objectives 5x, 10x, 20x N PLAN EPI objectives 2.5x–100x PLAN Fluotar objectives 1.25x–100x
Accessories	Fixed ergonomic stage (76 x 50 mm), left and right-hand operation or rotatable stage (76 x 50 mm) with wear-resistant ceramic surface or IL stage for large samples (up to 80 mm in height)

- O Lamellar Graphite, Objective Plan Fluotar 50x/0.80, Differential Interference Contrast
- ❷ Steel, Ferrit-Perlit, Objective Plan Fluotar 50x/0.80, Differential Interference Contrast
- 6 Steel C45, Ferrit-Perlit, Objective Plan Fluotar 10x/0.30, Differential Interference Contrast
- O Nodular Graphite, Objective Plan Fluotar 10x/0.30, Differential Interference Contrast
- S Nodular Graphite, Objective Plan Fluotar 10x/0.30, Differential Interference Contrast



